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Application/Control No.	Applicant(s)/Patent under Reexamination
10/717,834	LOKE ET AL.
Examiner	Art Unit
David Mis	2817

SEARCHED			
Class	Subclass	Date	Examiner
331	2, 8, 10, 11, 14, 16, 17, 18,	3/8/2005	DM
	25, 36C,		
	117R,		
	117FE,		
	117D,		
	177V,		
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INTERFERENCE SEARCHED			
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